# MOSFET – Power, Single N-Channel 60 V, 4.0 m $\Omega$ , 100 A

### **NVMYS4D1N06CL**

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	9		$V_{GS}$	±20	V
Continuous Drain Current Raic	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	100	Α
(Notes 1, 2, 3)	State	T <sub>C</sub> = 100°C		71	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	79	W
R <sub>θJC</sub> (Notes 1, 2)		T <sub>C</sub> = 100°C		40	
Continuous Drain Current R <sub>0.IA</sub>	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	22	Α
(Notes 1, 2, 3)	State	T <sub>A</sub> = 100°C		15	
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	3.7	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		1.8	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	820	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	100	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, I <sub>L(pk)</sub> = 5 A)			E <sub>AS</sub>	185	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	1.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

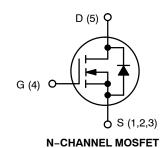
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



#### ON Semiconductor®

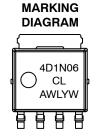
#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
60 V	4.0 mΩ @ 10 V	100 A
	5.7 mΩ @ 4.5 V	100 A





#### LFPAK4 CASE 760AB



4D1N06CL = Specific Device Code A = Assembly Location

WL =Wafer Lot Y = Year W = Work Week

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS					•			
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		60			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				28		mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	I <sub>DSS</sub> V <sub>CS</sub> = 0 V T <sub>J</sub>				10		
		$V_{GS} = 0 V$ , $V_{DS} = 48 V$	T <sub>J</sub> = 125°C			250	250 μA	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	= 20 V			100	nA	
ON CHARACTERISTICS (Note 4)					-			
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D} = 80 \mu A$		1.2		2.0	V	
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.4		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		3.3	4.0	$\dagger$	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 50 A		4.6	5.7	mΩ	
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub>	= 50 A		105		S	
CHARGES, CAPACITANCES & GATE RESIS	STANCE				-			
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			2200			
Output Capacitance	C <sub>OSS</sub>				900		pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>				17			
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 50 \text{ A}$ $V_{GS} = 10 \text{ V}, V_{DS} = 30 \text{ V}; I_D = 50 \text{ A}$			16			
Total Gate Charge	Q <sub>G(TOT)</sub>				34			
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 30 V; I <sub>D</sub> = 50 A			1.5		nC	
Gate-to-Source Charge	$Q_{GS}$				5.6			
Gate-to-Drain Charge	$Q_{GD}$				5.1			
Plateau Voltage	$V_{GP}$				2.8		V	
SWITCHING CHARACTERISTICS (Note 5)					-			
Turn-On Delay Time	t <sub>d(ON)</sub>				10			
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub>	s = 30 V,		15		1	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$I_D = 50 \text{ A}, R_G =$	2.5 Ω		24		ns	
Fall Time	t <sub>f</sub>				5.0		1 !	
DRAIN-SOURCE DIODE CHARACTERISTIC	s				-			
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.88	1.2	'	
		I <sub>S</sub> = 50 A	T <sub>J</sub> = 125°C		0.78		V	
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 50 A			41			
Charge Time	t <sub>a</sub>				21		ns	
Discharge Time	t <sub>b</sub>				20			
Reverse Recovery Charge	Q <sub>RR</sub>				32		nC	
	•				•			

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

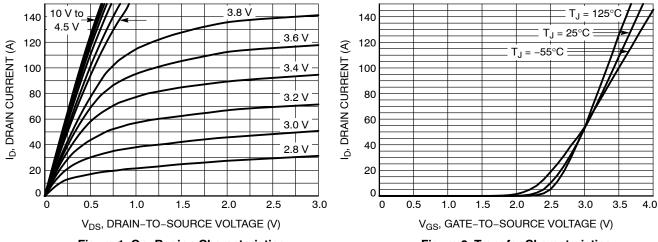


Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

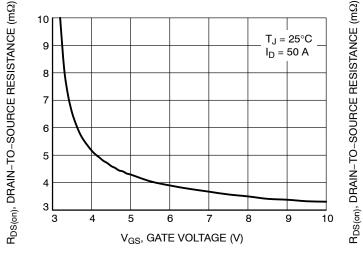


Figure 3. On-Resistance vs. Gate-to-Source Voltage

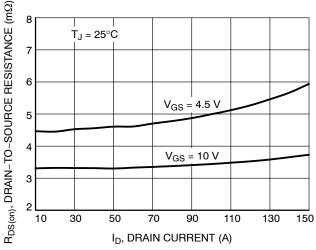


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

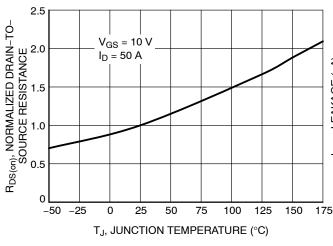


Figure 5. On–Resistance Variation with Temperature

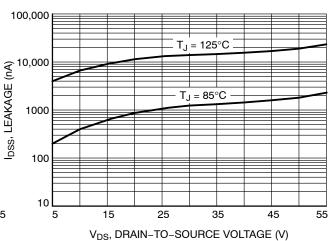
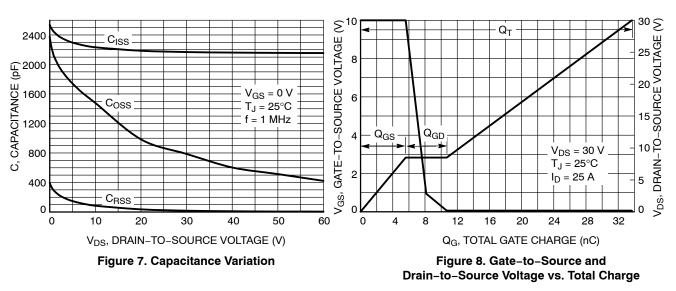


Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**



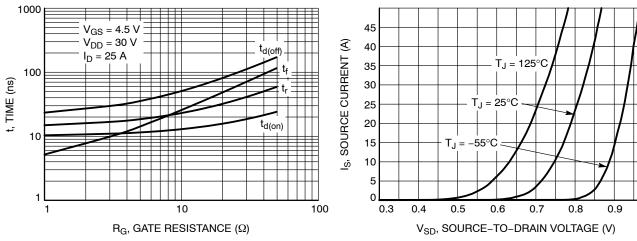


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

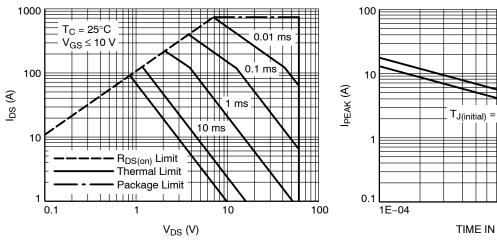


Figure 11. Safe Operating Area

10 T<sub>J(initial)</sub> = 25°C T<sub>J(initial)</sub> = 100°C T<sub>J(initial)</sub> = 100°

Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

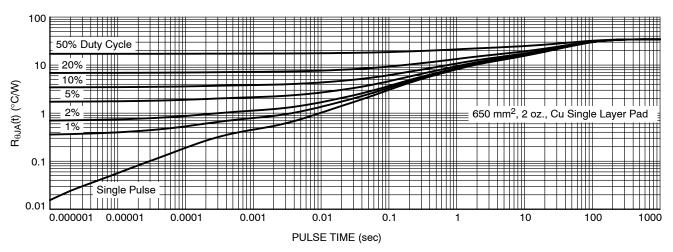
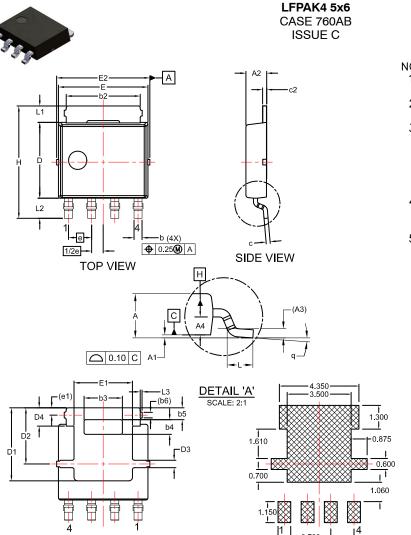


Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMYS4D1N06CLTWG	4D1N06CL	LFPAK4 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



**DATE 19 NOV 2019** 

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
- 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- 4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

UNIT IN MILLIMETER				
DIM	MIN	NOM	MAX	
Α	1.10	1.20	1.30	
A1	0.00	0.08	0.15	
A2	1.10	1.15	1.20	
A3	(	).25 REF	=	
A4	0.45	0.50	0.55	
b	0.40	0.45	0.50	
b2	3.80	4.10	4.40	
b3	2.00	2.10	2.20	
b4	0.70	0.80	0.90	
b5	0.55	0.65	0.75	
b6	_	0.31 REI		
С	0.19	0.22	0.25	
c2	0.19	0.22	0.25	
D	4.05	4.15	4.25	
D1	3.80	4.00	4.20	
D2	3.00	3.10	3.20	
D3	0.30	0.40	0.50	
D4	0.90	1.00	1.10	
Е	4.80	4.90	5.00	
E1	3.10	3.20	3.30	
E2	5.00	5.15	5.30	
е		1.27 BS0		
1/2e		0.635 BS		
e1	0,40 REF			
Н	6.00	6.15	6.30	
L	0.40	0.65	0.85	
L1	0.80	0.90	1.00	
L2	0.90	1.10	1.30	
L3	0.00	0.10	0.20	
q	0°	4°	8°	

#### RECOMMENDED LAND PATTERN

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

## GENERIC MARKING DIAGRAM\*

**BOTTOM VIEW** 



XXXXXX = Specific Device Code A = Assembly Location

WL = Wafer Lot
Y = Year

Y = Year W = Work Week

\*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

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